NEWS RELEASE
21 May 2010

PANalytical brings advanced XRF standardless analysis to the benchtop with Omnian and MiniPal 4

PANalytical (Almelo, the Netherlands) has extended the compatibility of its Omnian advanced standardless analysis software to now include the compact benchtop MiniPal 4 X-ray fluorescence (XRF) spectrometer. This combination offers a premium XRF solution that is both easy to use and extremely powerful. It is ideal for routine lab and field analysis, offering quantification of unknowns in situations where certified standards are not available.

Ready for any sample type, Omnian provides elemental analysis of all materials no matter how they have been prepared. Typical applications include rapid screening, comparative analysis and R&D investigations. In the default ‘black box’ mode, Omnian provides fast answers for industries such as: healthcare, pharmaceutical, food, environmental, oil, minerals and mining. Unlike traditional standardless approaches, Omnian data is both comprehensive and available for detailed review.

Incorporating cutting-edge technology, Omnian achieves superior accuracy, setting the benchmark for standardless analysis. This is achieved through the automatic use of PANalytical’s advanced Fundamental Parameters (FP) algorithm which deals with the analytical challenges posed by differing sample types. Other innovations include the support of multiple excitation conditions and the inclusion of several unique features. Fluorescence Volume Geometry (FVG) and Finite Thickness (FT) corrections, for example, improve accuracy when analyzing heavier elements in low density samples or samples with varying thicknesses. In addition, Adaptive Sample Characterization (ASC) minimizes particle size and mineralogical effects. This results in greater accuracy approaching the quality only achievable with dedicated calibration methods and standards.

For further information about how Omnian can help you meet your analytical challenges, visit: www.panalytical.com

Text Ends

Caption: MiniPal 4 and Omnian

For press information, please contact
Richard Kent, Kapler Communications
Knowledge Centre, Wyboston Lakes, Wyboston, Bedfordshire MK44 3BY UK
T: +44 (0) 1480 479280; F: +44 (0) 1480 470343 richard@kapleronline.com

For more press and product information:
PANalytical, Branding and Communications Dept.
T: +31 (0) 546 534444; F: +31 (0) 546 534592 info@panalytical.com